

Notice of References Cited	Application/Control No. 10/197,651	Applicant(s)/Patent Under Reexamination GAJDA, MARK A.	
	Examiner Walter L. Lindsay, Jr.	Art Unit 2812	Page 1 of 1

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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Sheet 1 of 1

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE		Atty. Docket No. GB 010121		Serial No. 10/197,651	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		Applicant MARK A. GAJDA			
		Filing 7/17/02		Group 2812	

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Ex. Int.		Document Number								Date	Name	Class	Sub-class	Filing Date If Approp.
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Examiner <i>William L. Turner</i>	Date Considered <i>9/03/03</i>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE				Atty. Docket No. GB 010121		Serial No.										
				Applicant Mark A. GAJDA												
				Filing Date CONCURRENTLY		Group										
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)																
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